Rochester Electronics

Datasheet

PART NUMBER

54F157B2A-ROC

Rochester Electronics Manufactured Components

Rochester branded components are manufactured using either die/wafers purchased from the original suppliers or Rochester wafers recreated from the original IP. All re-creations are done with the approval of the Original Component Manufacturer. (OCM)

Parts are tested using original factory test programs or Rochester developed test solutions to guarantee product meets or exceeds the OCM data sheet.

Quality Overview

- ISO-9001
- AS9120 certification
- Qualified Manufacturers List (QML) MIL-PRF-38535
    - Class Q Military
    - Class V Space Level

Qualified Suppliers List of Distributors (QSLD)

- Rochester is a critical supplier to DLA and meets all industry and DLA standards.

Rochester Electronics, LLC is committed to supplying products that satisfy customer expectations for quality and are equal to those originally supplied by industry manufacturers.

The original manufacturer's datasheet accompanying this document reflects the performance and specifications of the Rochester manufactured version of this device. Rochester Electronics guarantees the performance of its semiconductor products to the original OCM specifications. 'Typical' values are for reference purposes only. Certain minimum or maximum ratings may be based on product characterization, design, simulation, or sample testing.

National Semiconductor

MILITARY DATA SHEET

MN54F157A-X REV 1A0

Original Creation Date: 03/14/96
Last Update Date: 07/30/96
Last Major Revision Date: 03/14/96

QUAD 2-INPUT Multiplexer

General Description

The F157A is a high-speed quad 2-Input multiplexer. Four bits of data from two sources can be selected using the common Select and Enable inputs. The four buffered outputs present the selected data in the true (non-inverted) form. The F157A can also be used to generate any four of the 16 different functions to two variables.

Industry Part Number

54F157A

NS Part Numbers

54F157ADMQB
54F157AFMQB
54F157ALMQB

Prime Die

M157A

Processing

MIL-STD-883, Method 5004

Quality Conformance Inspection

MIL-STD-883, Method 5005

Subgrp	Description	Temp (°C)
1	Static tests at	+25
2	Static tests at	+125
3	Static tests at	-55
4	Dynamic tests at	+25
5	Dynamic tests at	+125
6	Dynamic tests at	-55
7	Functional tests at	+25
8A	Functional tests at	+125
8B	Functional tests at	-55
9	Switching tests at	+25
10	Switching tests at	+125
11	Switching tests at	-55

Features

- Guaranteed 4000V minimum ESD protection

(Absolute Maximum Ratings)

(Note 1)

Storage Temperature	-65 C to +150 C
Ambient Temperature under Bias	-55 C to +125 C
Junction Temperature under Bias	-55 C to +175 C
Vcc Pin Potential to Ground Pin	-0.5V to +7.0V
Input Voltage (Note 2)	-0.5V to +7.0V
Input Current (Note 2)	-30 mA to +5.0mA
Voltage Applied to Output in HIGH State (with Vcc=0V)	
Standard Output	-0.5V to Vcc
TRI-STATE Output	-0.5V to +5.5V
Current Applied to Output in LOW State (Max)	twice the rated Iol(mA)
ESD Last Passing Voltage (Min)	4000V

Note 1: Absolute Maximum ratings are those values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.
Note 2: Either voltage limit or current limit is sufficient to protect inputs.

Recommended Operating Conditions

Free Air Ambient Temperature	
Commercial	0 C to +70 C
Military	-55 C to +125 C
Supply Voltage	
Military	+4.5V to +5.5V
Commercial	+4.5V to +5.5V

Electrical Characteristics

DC PARAMETER

(The following conditions apply to all the following parameters, unless otherwise specified.)
DC: VCC 4.5V to 5.5V, Temp range: -55C to 125C

SYMBOL	PARAMETER	CONDITIONS	NOTES	PIN-NAME	MIN	MAX	UNIT	SUB-GROUPS
IIH	Input High Current	VCC=5.5V, VM=2.7V, VINH=5.5V, VINL=0.0V	1, 3	INPUTS		20	uA	1, 2, 3
IBVI	Input High Current	VCC=5.5V, VM=7.0V, VINH=5.5V, VINL=0.0V	1, 3	INPUTS		100	uA	1, 2, 3
IIL	Input LOW Current	VCC=5.5V, VM=0.5V, VINH=5.5V, VINL=0.0V	1, 3	INPUTS		-0.6	mA	1, 2, 3
VOL	Output LOW Voltage	VCC=4.5V, VIL=0.8V, VIH=2.0V, IOL=20mA, VINL=0.0V, VINH=5.5V	1, 3	OUTPUTS		0.5	V	1, 2, 3
VOH	Output HIGH Voltage	VCC=4.5V, VIL=0.8V, IOH=-1.0mA, VIH=2.0V, VINL=0.0V, VINH=5.5V	1, 3	OUTPUTS	2.5		V	1, 2, 3
IOS	Short Circuit Current	VCC=5.5V, VINH=5.5V, VM=0.0V, VINL=0.0V	1, 3	OUTPUTS	-60	-150	mA	1, 2, 3
VCD	Input Clamp Diode Voltage	VCC=4.5V, IM=-18mA, VINH=5.5V	1, 3	INPUTS		-1.2	V	1, 2, 3
ICC	Supply Current	VCC=5.5V, VINH=5.5V	1, 3	VCC		23	mA	1, 2, 3
ICEX	Output HIGH Leakage Current	VCC=5.5V, VINH=5.5V, VINL=0.0V, VM=5.5V	1, 3	OUTPUTS		250	uA	1, 2, 3

AC PARAMETER

(The following conditions apply to all the following parameters, unless otherwise specified.)
AC: CL=50pf, RL=500 OHMS, TR=2.5ns, TF=2.5ns SEE AC FIGS

tpLH(1)	Propagation Delay	VCC=5.0V @25C, VCC=4.5V & 5.5V @-55/125C	2, 4	In to Zn	2.5	6.0	ns	9
			2, 4	In to Zn	2.5	7.5	ns	10, 11
tpHL(1)	Propagation Delay	VCC=5.0V @25C, VCC=4.5V & 5.5V @-55/125C	2, 4	In to Z	2.5	5.5	ns	9
			2, 4	In to Z	1.5	7.5	ns	10, 11
tpLH(2)	Propagation Delay	VCC=5.0V @25C, VCC=4.5V & 5.5V @-55/125C	2, 4	S to Zn	4.0	10.0	ns	9
			2, 4	S to Zn	4.0	12.0	ns	10, 11
tpHL(2)	Propagation Delay	VCC=5.0V @25C, VCC=4.5V & 5.5V @-55/125C	2, 4	S to Zn	3.0	7.0	ns	9
			2, 4	S to Zn	3.0	9.0	ns	10, 11
tpLH(3)	Propagation Delay	VCC=5.0V @25C, VCC=4.5V & 5.5V @-55/125C	2, 4	$\overline{E}$ to Zn	5.0	9.5	ns	9
			2, 4	$\overline{E}$ to Zn	5.0	13.0	ns	10, 11
tpHL(3)	Propagation Delay	VCC=5.0V @25C, VCC=4.5V & 5.5V @-55/125C	2, 4	$\overline{E}$ to Zn	2.5	6.5	ns	9
			2, 4	$\overline{E}$ to Zn	2.5	7.5	ns	10, 11

Note 1: Screen tested 100% on each device at +25C, +125C & -55C temperature, subgroups A1, 2, 3, 7 & 8.

(Continued)

Note 2: Screen tested 100% on each device at +25C temperature only, subgroup A9.
Note 3: Sample tested (Method 5005, Table 1) on each MFG. lot at +25C, +125C & -55C temperature, subgroups A1, 2, 3, 7 & 8.
Note 4: Sample tested (Method 5005, Table 1) on each MFG. lot at +25C subgroup A9, and periodically at +125C & -55C temperature, subgroups 10 & 11.